

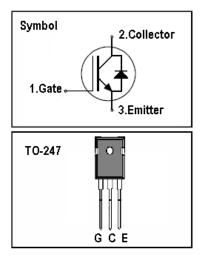
# IGBT

#### Features

- 1200V,15A
- V<sub>CE(sat)(typ.)</sub>=2.5V@V<sub>GE</sub>=15V,I<sub>C</sub>=15A
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA using NPT technology

### **General Description**

KEDA NPT IGBTs offer lower losses and higher energy efficiency for application such as IH (induction heating),UPS, general inverter and other soft switching applications.



**KDG15N120H** 

## Absolute Maximum Ratings

Symbol	Parameter	Value	Units	
V <sub>CES</sub>	Collector-Emitter Voltage	1200	V	
$V_{\text{GES}}$	Gate-Emitter Voltage	<u>+</u> 30	V	
	Continuous Collector Current ( T_c=25 $^\circ\!\!\!{}^\circ\!\!\!{}^\circ$ )	30	A	
I <sub>C</sub>	Continuous Collector Current ( $T_c=100^{\circ}$ )	15	A	
I <sub>CM</sub>	I <sub>CM</sub> Pulsed Collector Current (Note 1)		A	
I <sub>F</sub>	Diode Continuous Forward Current ( $T_c=100$ $^{\circ}C$ )	15	A	
I <sub>FM</sub>	I <sub>FM</sub> Diode Maximum Forward Current (Note 1)		A	
t <sub>sc</sub>	t <sub>sc</sub> Short Circuit Withstand Time		us	
D	Maximum Power Dissipation ( T <sub>c</sub> =25 $^{\circ}$ C )	170	W	
P <sub>D</sub>	Maximum Power Dissipation ( $T_C=100^{\circ}C$ )	68	W	
TJ	Operating Junction Temperature Range	-55 to +150	°C	
T <sub>STG</sub>	T <sub>STG</sub> Storage Temperature Range		°C	

#### **Thermal Characteristics**

Symbol	Parameter	Max.	Units	
R <sub>th j-c</sub>	R <sub>th j-c</sub> Thermal Resistance, Junction to case for IGBT		°C / W	
R <sub>th j-c</sub>	R <sub>th j-c</sub> Thermal Resistance, Junction to case for Diode		°C / W	
R <sub>th j-a</sub>	Thermal Resistance, Junction to Ambient	40	°C / W	



### **Electrical Characteristics** ( $T_c=25^{\circ}$ unless otherwise noted )

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250uA	1200	-	-	V
I <sub>CES</sub>	Collector-Emitter Leakage Current	V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V	-	-	250	uA
	Gate Leakage Current, Forward	$V_{GE}$ =30V, $V_{CE}$ = 0V	-	-	100	nA
GES	Gate Leakage Current, Reverse	$V_{GE}$ = -30V, $V_{CE}$ = 0V	-	-	-100	nA
V <sub>GE(th)</sub>	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 250 \text{uA}$	4.0	-	6.0	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	V <sub>GE</sub> =15V, I <sub>C</sub> = 20A	-	2.5		V
Qg	Total Gate Charge	V <sub>cc</sub> =960V	-	68		nC
Qge	Gate-Emitter Charge	V <sub>GE</sub> =15V	-	22		nC
Q <sub>gc</sub>	Gate-Collector Charge	I <sub>C</sub> =15A	-	23		nC
t <sub>d(on)</sub>	Turn-on Delay Time	$V_{CC}$ =600V $V_{GE}$ =15V $I_{C}$ =15A $R_{G}$ =28 $\Omega$ Inductive Load $T_{C}$ =25 °C	-	32	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	38	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	223	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	74	-	ns
Eon	Turn-on Switching Loss		-	1.6	-	mJ
Eoff	Turn-off Switching Loss		-	0.6	-	mJ
Ets	Total Switching Loss		-	2.2	-	mJ
Cies	Input Capacitance	V <sub>CF</sub> =25V	-	481	-	pF
Coes	Output Capacitance	V <sub>GE</sub> =0V	-	89	-	pF
Cres	Reverse Transfer Capacitance	f = 100kHz	-	28	-	pF
R <sub>Gint</sub>	Integrated gate resistor			3.8		Ω

### **Electrical Characteristics of Diode** ( $T_c=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> =15A	-	1.4	2.8	V
t <sub>rr</sub>	Diode Reverse Recovery Time	V <sub>CE</sub> = 600V	-	180		ns
l <sub>rr</sub>	Diode peak Reverse Recovery Current	I <sub>F</sub> = 15A	-	26		А
Q <sub>rr</sub>	Diode Reverse Recovery Charge	dI <sub>F</sub> /dt = 500A/us	-	2875		nC

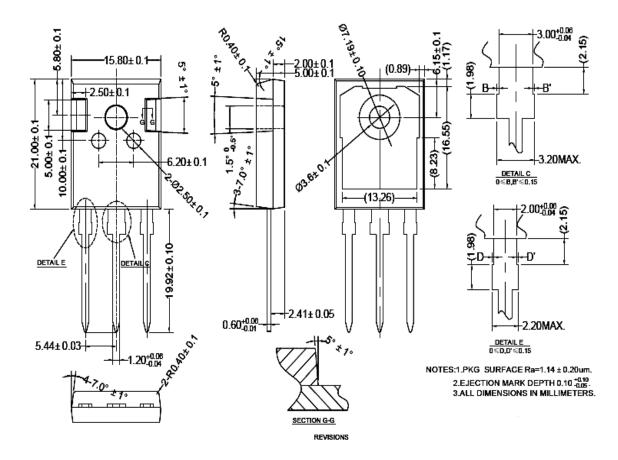
#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature



# **KDG15N120H**

#### **TO247 PACKAGE OUTLINE**



会差标注	公差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4

#### 0≤D,D'≤0.15

NOTES:1.PKG\_SURFACE Ra=1.14 ± 0.20um. 2.EJECTION MARK DEPTH 0.10 +0.10 -0.05 3.ALL DIMENSIONS IN MILLIMETERS.



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